

### LOW NOISE HIGH FREQUENCY PACKAGED pHEMT

### Package: P70

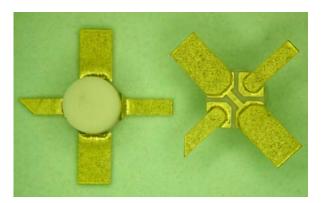


### **Product Description**

The FPD7612P70 is a low parasitic, surface mountable packaged depletion mode pseudomorphic High Electron Mobility Transistor (pHEMT) optimized for low noise, high frequency applications.



- Si BJT
- GaN HEMT
- InP HBT
- RF MEMS
- LDMOS



### **Features**

- 22dBm Output Power (P1dB)
- 21dB Gain at 1.85GHz
- 0.5 dB Noise Figure at 1.85 GHz
- 30dB Output IP<sub>3</sub> at 1.85GHz
- 45% Power-Added Efficiency at 1.85GHz
- Usable Gain to 24GHz

### **Applications**

- Gain blocks and medium power stages
- WiMax (2GHz to 11GHz)
- WLAN 802.11a (5.8GHz)
- Point-to-Point Radio (to 18GHz)

RF Parameter	Typical Performance		Unit	Condition		
RF Falameter	Min. Typ. M		Max.	Unit	Condition	
P <sub>1dB</sub> at Gain Compression		20		dBm	V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA	
Small-Signal Gain (SSG)	19	21		dB	V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA	
PAE		45		%	V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA, P <sub>OUT</sub> =P <sub>1dB</sub>	
Maximum Stable Gain ( S21/S12 )		14			V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA, f=12GHz	
		10			V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA, f=18GHz	
Noise Figure (NF)		0.5		dB	V <sub>DS</sub> =5V, I <sub>DS</sub> =15mA	
OIP <sub>3</sub>		30		dBm	V <sub>DS</sub> =5V, I <sub>DS</sub> =30mA, P <sub>OUT</sub> =10dBm SCL	
Saturated Drain-Source Current (I <sub>DSS</sub> )	45	60	75	mA	V <sub>DS</sub> =1.3V, V <sub>GS</sub> =0V	
Maximum Drain-Source Current (I <sub>MAX</sub> )		120		mA	$V_{DS}$ =1.3V, $V_{GS}$ =+1V	
Transconductance (GM)		80		ms	V <sub>DS</sub> =1.3V, V <sub>GS</sub> =0V	
Gate-Source Leakage Current (I <sub>GSO</sub> )		1	10	μΑ	V <sub>GS</sub> =-5V	
Pinch-Off Voltage (V <sub>P</sub> )	0.7	0.9	1.3	V	V <sub>DS</sub> =1.3V, I <sub>DS</sub> =0.2mA	
Gate-Source Breakdown Voltage (V <sub>BDGS</sub> )	12	14		V	I <sub>GS</sub> =0.2mA	
Gate-Drain Breakdown Voltage (V <sub>BDGD</sub> )	14.5	16		V	I <sub>DS</sub> =0.2mA	
Thermal Resistivity (θJC) *		335		°C/W		

\*Note: T<sub>AMBIENT</sub>=22°C, RF specification measured at f=1.85GHz using CW signal (except as noted).

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#### rfmd.com

### Absolute Maximum Ratings<sup>1</sup>

0		
Parameter	Rating	Unit
Drain-Source Voltage (V <sub>DS</sub> ) (-3V <v<sub>GS&lt;-0.5V)</v<sub>	8	V
Gate-Source Voltage (V <sub>GS</sub> ) (0V < V <sub>DS</sub> < +8V)	-3	V
Drain-Source Current $(I_{DS})$ (For $V_{DS}$ <2V)	I <sub>DSS</sub>	
Gate Current (I <sub>G</sub> ) (Forward or reverse)	5	mA
RF Input Power $(P_{IN})^2$ (Under any acceptable bias state)	16	dBm
Channel Operating Temperature (T <sub>CH</sub> ) (Under any acceptable bias state)	175	°C
Storage Temperature (T <sub>STG</sub> ) (Non-Operating Storage)	-40 to 150	°C
Total Power Dissipation (P <sub>TOT</sub> ) <sup>3, 4, 5</sup>	450	mW
Simultaneous Combination of Limits <sup>6</sup> (2 or more max. limits)	80	%

Notes:

 $^{1}T_{AMBIENT}$  = 22 °C unless otherwise noted; exceeding any one of these absolute maximum ratings may cause permanent damage to the device.

 $^{3}\mbox{Users}$  should avoid exceeding 80% of 2 or more Limits simultaneously.

<sup>4</sup>Total Power Dissipation (P<sub>TOT</sub>) defined as (P<sub>DC</sub>+P<sub>IN</sub>)-P<sub>OUT</sub>, where P<sub>DC</sub>: DC Bias Power, P<sub>IN</sub>: RF Input Power, P<sub>OUT</sub>: RF Output Power.

Total Power Dissipation to be de-rated as follows above 22 °C:  $P_{TOT}=0.45-(1/R\theta JC) \times T_{PACK}$ , where  $T_{PACK}$ =source tab lead temperature above 22 °C.

Example: For a 65 °C carrier temperature:  $P_{TOT}$ =470 mW-(3x(65-22))=321 mW

### **Biasing Guidelines**

Active bias circuits provide good performance stabilization over variations of operating temperature, but require a larger number of components compared to self-bias or dual-biased. Such circuits should include provisions to ensure that gate bias is applied before drain bias, otherwise the pHEMT may be induced to self-oscillate.

Dual-bias circuits are relatively simple to implement, but will require a regulated negative voltage supply for depletion-mode devices such as the FPD7612P70.

For standard Class A operation, a 50% of  $I_{DSS}$  bias point is recommended. A small amount of RF gain expansion prior to the onset of compression is normal for this operating point. Class AB of 25% to 33% of  $I_{DSS}$  offers an optimized solution for NF and  $OIP_3$ .



**Caution!** ESD sensitive device.

Exceeding any one or a combination of the Absolute Maximum Rating conditions may cause permanent damage to the device. Extended application of Absolute Maximum Rating conditions to the device may reduce device reliability. Specified typical performance or functional operation of the device under Absolute Maximum Rating conditions is not implied.

RoHS status based on EUDirective 2002/95/EC (at time of this document revision).

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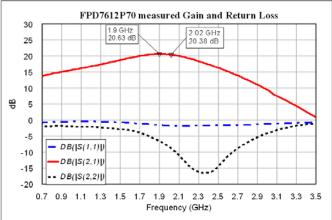
<sup>&</sup>lt;sup>2</sup>Max. RF input limit must be further limited if input VSWR>2.5:1.

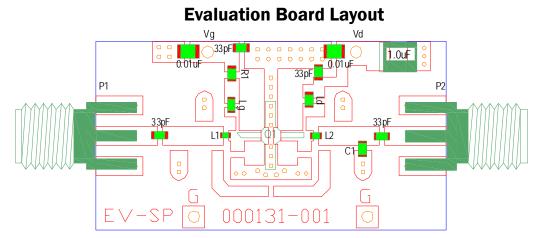


### **Reference Design (2.0GHz)**

Parameter	Typ at 1.90GHz	Typ at 1.96GHz	Typ at 2.02GHz	Unit	Bias		30	Г
Gain	20.6	20.5	20.4	dB	V <sub>D</sub> =3V,		25	┢
P1dB	15.0	14.8	14.8	dBm	I <sub>D</sub> =30mA		20	$\vdash$
0IP3 <sup>1</sup>	27.5	27.5	28.0	dBm			15	F
NF	0.65	0.58	0.65	dB			10	⊢
Gain	20.0	19.7	20.4	dB	V <sub>D</sub> =5V,	뜅	5	╞
P1dB	17.5	17.8	18.0	dBm	I <sub>D</sub> =30mA		0	F
0IP3 <sup>1</sup>	27.0	27.0	27.1	dBm			-5	ŀ
NF	0.67	0.60	0.65	dB			-10	ŀ

 $^1 \text{OIP3}$  measured at POUT of 2dBm per tone with spacing=5MHz.

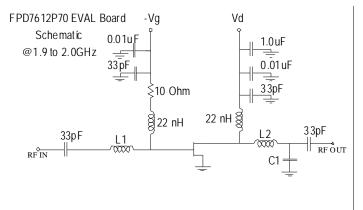




### **Component Values**

Component	Value	Description
Lg, Ld	22nH	LL 1608FSL Toko chip inductor
L1	4.7 nH	LL 1005FHL Toko chip inductor
L2	3.9nH	LL 1005FHL Toko chip inductor
C1	0.5 pF	ATC 600S chip capacitor
33pFx4	33pF	ATC 600S chip capacitor
0.01µFx4	0.01µF	ATC 0805X7R chip capacitor
1.0µF	1.0µF	B-Case Tantallum chip capacitor
R1	10Ω	0603 size chip resistor (100mW)
P1, P2		PCB Edge mount RF connector

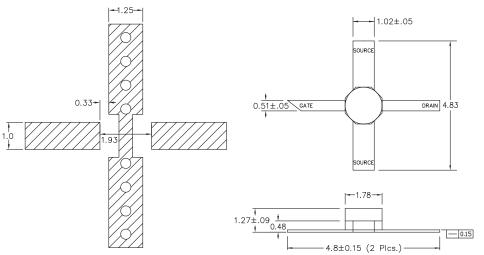
Evaluation board material: 31 mil thick Rogers 4003 with 1/2 oz. Cu on both sides.





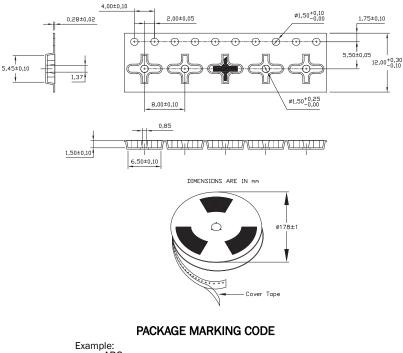
### P70 Package Outline and Recommended PC Board Layout

Dimensions in millimeters



### **Tape and Reel Dimensions and Part Orientation**

Tape and reel information on this material is in accordance with EIA-481-1 except where exceptions are identified.



Example: ABC A=product type B=week code C=year code Reel: Terminal tape=40mm (min) Leader tape with empty cavities=350mm (min) Trailer tape with empty cavities=160mm (min) Devices per reel=1000



### **Preferred Assembly Instructions**

ATTENTION

**Observe Precautions** 

for Handling Electrostatic Sensitive Devices

This package is compatible with both lead free and leaded solder reflow processes as defined within IPC/JEDEC J-STD-020C. The maximum package temperature should not exceed 260 °C. Package leads are gold plated.



To avoid damage to the devices, care should be exercised during handling. Proper Electrostatic Discharge (ESD) precautions should be observed at all stages of storage, handling, assembly, and testing. storage, handling, assembly, and testing.

### **ESD** Rating

These devices should be treated as Class 0 (0V to 250V) using the human body model as defined in JEDEC Standard No. 22-A114. Further information on ESD control measures can be found in MIL-STD-1686 and MIL-HDBK-263.

### **MSL** Rating

The device has an MSL rating of Level 1. To determine this rating, preconditioning was performed to the device per the Pb-free solder profile defined within IPC/JEDEC J-STD-020C, moisture / reflow sensitivity classification for non-hermetic solid state surface mount devices.

### **Application Notes and Design Data**

Application Notes and design data including S-parameters, noise parameters, and device model are available on request and from www.rfmd.com.

### Reliability

An MTTF of 4.2 million hours at a channel temperature of 150 °C is achieved for the process used to manufacture this device.

### **Disclaimers**

This product is not designed for use in any space-based or life-sustaining/supporting equipment.

### **Ordering Information**

Description	Ordering Code
RoHS-Compliant Packaged pHEMT	FPD7612P70
2.0 GHz Evaluation Board	EB7612P70-AC

Quantity	Ordering Code
Reel of 1000	FPD7612P70
Reel of 100	FPD7612P70SR
Bag of 25	FPD7612P70SQ
Bag of 5	FPD7612P70SB



